

Search Notes

Application/Control No.

10/541,327

Examiner

Nguyen N. Hanh

Applicant(s)/Patent under
Reexamination

SHIMIZU ET AL.

Art Unit

2834

SEARCHED

Class	Subclass	Date	Examiner
310	156.01- 156.84	6/20/2006	HN
310	261	6/20/2006	HN
310	262	6/20/2006	HN
310	218	6/20/2006	HN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR